FORM PTO 1449 (modified)					ATTY DOCKET NO. 35.C14089	APPLICATION NO. 09/443,308							
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OF FIGURE E					APPLICANT								
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)					TOSHIAKI AIBA ET AL.								
				<u> </u>	Nov mb r 19, 1999	GROUP 2879							
U.S. PATENT DOCUMENTS *EXAMINER DOCUMENT DATE NAME CLASS SUBCLASS IF APPROPRIATE													
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	ÇLASS	SUBCLASS	FILING DATE IF APPROPRIATE					
gw/		6,008,569	12/28/99		Yamanobe	313	310	10/30/97					
kw		6,005,334	12/21/99		Mitome et al.	313	309	4/28/97					
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		DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT					
gw		7-235255	9/5/95		Japan			Abstract					
AN		2836015	10/9/98		Japan	_		Abstract					
AW		2903295	3/26/99		Japan	_		Abstract					
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Oseph Williams
5/1/03

Sheet 1 of 1

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FORM PTO 14		MERCAHS 1 3 2001 W	ATTY DOCKET NO. 35.C14089	APPLICAT	10N NO. 09/443,3	808							
. LIST	U.S. DEFARTMENT OF CON *PATENT AND TRADEMARK OF REFERENCES CITED BY	MERAHS 1 3 2001 LL SEFFICE APPLICANT(S) SS (2)	APPLICANT TOSHIAKI AIBA ET AL.										
	OF REFERENCES CITED BY (Use several sheets if nece	RADEMARK	FILING DATE Nov mb r 19, 1999	ILING DATE Nov mb r 19, 1999									
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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE							
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gn	8-321254	12/96	Japan			Abstract							
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<i>U</i>													
		OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		<u> </u>								
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EXAMINER Joseph Williams			DATE CONSIDERED 5/1/03										

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.